

Performing a 32-bit test

DTEST(P)

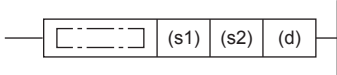
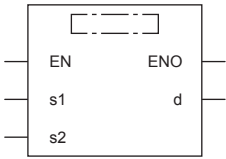
FX5S

FX5UJ

FX5U

FX5UC

These instructions take bit data at position specified by (s2) from device specified by (s1) and write to bit device specified by (d).

Ladder diagram	Structured text
	<pre>ENO:=DTEST(EN,s1,s2,d); ENO:=DTESTP(EN,s1,s2,d);</pre>
FBD/LD	
	

Setting data

■Descriptions, ranges, and data types

Operand	Description	Range	Data type	Data type (label)
(s1)	Device number where bit data to be extracted is stored	—	32-bit signed binary	ANY32
(s2)	Position of bit data to be extracted	0 to 31	16-bit unsigned binary	ANY16
(d)	Bit device number where extracted bit data is to be stored	—	Bit	ANY_BOOL
EN	Execution condition	—	Bit	BOOL
ENO	Execution result	—	Bit	BOOL

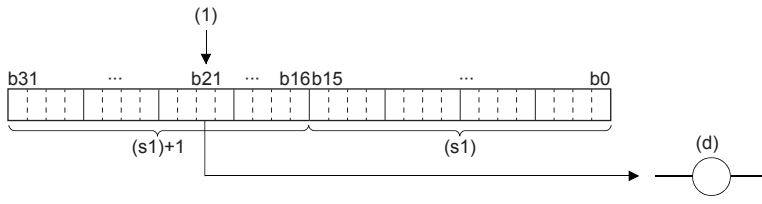
■Applicable devices

Operand	Bit	Word			Double word		Indirect specification	Constant			Others
	X, Y, M, L, SM, F, B, SB, S	T, ST, C, D, W, SD, SW, R	U□\G□	Z	LC	LZ		K, H	E	\$	
(s1)	○	○	○	○	○	○	○	—	—	—	—
(s2)	○	○	○	○	—	—	○	○	—	—	—
(d)	○	○*1	○	—	—	—	—	—	—	—	—

*1 T, ST, and C cannot be used.

Processing details

- These instructions take bit data at position specified by (s2) from device specified by (s1), (s1) + 1 and write to bit device specified by (d).



(1): (s2) bit (When (s2)=21)

- If relevant bit is "0", device specified by (d) is turned OFF, and if it is "1", device is turned ON.
- For (s2) specify the bit position (0 to 31) of double word data. If 32 or more is specified for (s2), the value of the remainder of $(s2) \div 32$ is the bit position.

Ex.

For (s2) = 34, the remainder for $34 \div 32$ is "2", so it becomes data of b2.

Operation error

There is no operation error.